





Sheet 1 of 2

<b>FORM PTO-1449</b> (REV. 8-89) <b>INFORMATION DISCLOSURE CITATION</b>  (Use several sheets if necessary)	<b>U.S. DEPARTMENT OF COMMERCE</b> Patent and Trademark Office		<b>Attorney's Docket No.</b> 20830-06581	<b>Serial No.</b> 10/029,957
	<b>Applicant</b> Steven W. Meeks			
	<b>Filing Date</b> 12/21/2001		<b>Group Art Unit</b> Not Yet Known	

**U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
TN	A	3,885,875	05/27/75	Rosenfeld et al.	356	120	
	B	4,332,477	06/01/82	Sato	356	371	
	C	4,668,860	05/26/87	Anthon	250	225	
	D	4,873,430	10/10/89	Juliana et al.	250	225	
	E	5,017,012	05/21/91	Merritt, Jr. et al.	356	371	
	F	5,129,724	07/14/92	Brophy et al.	356	357	
	G	5,196,906	03/23/93	Stover et al.	356	446	
	H	5,293,216	03/08/94	Moslehi	356	371	
	I	5,313,542	05/17/94	Castonguay	385	115	
	J	5,406,082	04/11/95	Pearson et al.	250	339.01	
TN	K	5,446,549	08/29/95	Mazumder et al.	356	376	

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
TN	L	3-221804		Japan				

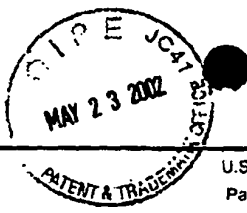
**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

TN	M	W.C. Leung, W. Crooks, H. Rosen and T. Strand, <i>An Optical Method Using a Laser and an Integrating Sphere Combination for Characterizing the Thickness Profile of Magnetic Media</i> , Sept. 1989, IEEE Transaction on Magnetics, Vol. 25, No. 5. Pages 3659-3661.
TN	N	Steven W. Meeks, Walter E. Weresin, and Hal J. Rosen, <i>Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks</i> , January 1995, Transactions of the ASME, Journal of Tribology, Vol. 117, pages 112-118.
TN	O	Steven Meeks, Maxtor and Rusmin Kudinar, <i>The Next Battleground: Head-Disk Interface</i> , March 1998, Data Storage, Test & Measurement, pages 29-30, 34 and 38.
TN	P	<i>Laser Scanning Surface Profilometer</i> , [online], August 1970, [retrieved January 29, 2001], Pages 789-790, Retrieved from the Internet: <URL: <a href="http://www.delphion.com/tbbs/tdb?&amp;order=70C101758">http://www.delphion.com/tbbs/tdb?&amp;order=70C101758</a> >.

<b>EXAMINER</b> TN	<b>DATE CONSIDERED</b> 9/28/03
<b>EXAMINER:</b> Initial if references considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

PTO-1449  
REV: 02/01

20830/06581/DOCS/1263108.1



<b>FORM PTO-1449</b> (REV. 6-89) <b>INFORMATION DISCLOSURE CITATION</b>  (Use several sheets if necessary)	<b>U.S. DEPARTMENT OF COMMERCE</b> Patent and Trademark Office	<b>Attorney's Docket No.</b> 20830-06581	<b>Serial No.</b> 10/029,957
	<b>Applicant</b> Steven W. Meeks		
	<b>Filing Date</b> 12/21/2001	<b>Group Art Unit</b> Not Yet Known	

**U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TN	Q	5,463,897	11/07/95	Prater et al.	73	105	
	R	5,608,527	03/04/97	Valliant et al.	356	371	
	S	5,610,897	03/11/97	Yamamoto et al.	369	124	
	T	5,644,562	07/01/97	de Groot	369	110	
	U	5,694,214	12/02/97	Watanabe et al.	356	237	
	V	5,726,455	03/10/98	Vurens	250	559.28	
	W	5,748,305	05/05/98	Shimono et al.	356	237	
	X	5,777,740	07/07/98	Lacey et al.	356	357	
	Y	5,875,029	02/23/99	Jann et al.	356	345	
	Z	5,951,891	09/14/99	Barenboim et al.	219	121.68	
	AA	5,978,091	11/02/99	Jann et al.	356	376	
	BB	5,985,680	11/16/99	Singhal et al.	438	7	
	CC	5,986,761	11/16/99	Crawforth et al.	356	371	
	DD	6,088,092	07/11/00	Chen et al.	356	237.2	
	EE	6,118,525	09/12/00	Fossey et al.	356	237.2	
	FF	6,134,011	10/17/00	Klein et al.	356	369	
	GG	6,157,444	12/05/00	Tomitka et al.	356	237.1	
TN	HH	6,172,752	01/09/01	Haruna et al.	356	357	

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

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PTO/SB/08A (10-01)  
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Substitute for form 1449A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application No.	10/029,957
				Filing Date	12/21/2001
				First Named Inventor	Steven W. Meeks
				Art Unit	2877
				Examiner Name	Not Yet Known
Sheet	1	of	1	Attorney Docket Number	20830-06581

U.S. PATENT DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Document No. Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
TN	A	US-4585348	04/29/1986	Chastang <i>et al.</i>
TN	B	US-5995226	11/30/1999	Abe <i>et al.</i>

FOREIGN PATENT DOCUMENTS					
		Foreign Patent Document			
Examiner Initials*	Cite No. <sup>1</sup>	Country Code <sup>3</sup> – Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T <sup>6</sup>
TN	C	WO98/52019	11/19/1998	Klaas Hemmes <i>et al.</i>	

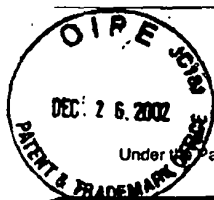
OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T <sup>6</sup>
TN	D	Meeks, Steven W.: "A Combined Ellipsometer, Reflectometer, Scatterometer and Kerr Effect Microscope for Thin Film Disk Characterization," Machine Vision Applications in Industrial Inspection VIII, Proceedings of SPIE, vol. 3966, 2000, pages 385-391, XP001085220.			

Examiner Signature	TN	Date Considered	9/28/03
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<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

20830/06581/DOCS/1288263.1



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<b>Substitute for form 1449A/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		<b>Complete if Known</b>			
		Application No.	10/029,957		
		Filing Date	12/21/2001		
		First Named Inventor	Steven W. Meeks		
		Art Unit	2877		
		Examiner Name	Not Yet Known		
Sheet	1	of	1	Attorney Docket Number	20830-06581

U.S. PATENT DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Document No. Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
TN	A1	US-5633747	05/27/1997	Nikoonahad
	A2	US-5864394	01/26/1999	Jordan, III et al.
	A3	US-6081325	06/27/2000	Leslie et al.
	A4	US-6248988	06/19/2001	Krantz
TN	A5	US-6307627	10/23/2001	Vurens

FOREIGN PATENT DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> - Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		<i>None</i>		

OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS				
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		<i>None</i>		

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20830/06581/DOCS/1303371.1



Substitute for form 1449A/PTO		Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application No.	10/029,957
		Filing Date	December 21, 2001
		First Named Inventor	Steven W. Meeks
		Art Unit	2877
		Examiner Name	Unknown
Sheet 1 of 1	Attorney Docket Number	20830-06581	

U.S. PATENT DOCUMENTS				
Examiner Initials*	Cite No.	Document No. Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
TR		US-5,880,838	03/09/1999	Marx et al.

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U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application N .	10/029,957
				Filing Dat	December 21, 2001
				First Named Inventor	Steven W. Meeks
				Art Unit	2877
				Examiner Name	Not Yet Known
Sheet	1	of	1	Attorney Docket Number	20832-06581

U.S. PATENT DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Document No. Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
TN	A1	US 5,189,481	02/23/1993	Jann et al.
	A2	US 5,416,594	05/16/1995	Gross et al.
	A3	US 5,798,829	08/25/1998	Vaez-Iravani
	A4	US 5,903,342	05/11/1999	Yatsugake et al.
	A5	US 6,091,493	07/18/2000	Stover et al.
	A6	US 6,201,601B1	03/13/2001	Vaez-Iravani et al.
	A7	US 6,271,916B1	08/07/2001	Marxer et al.
	A8	US 6,384,910B2	05/07/2002	Vaez-Iravani et al.
TN	A9	US 6,509,966B2	01/21/2003	Ishiguro et al.

FOREIGN PATENT DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
				T <sup>6</sup>

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20830/06581/DOCS/1373116.1